

SID4-HR

WAVE FRONT SENSOR



↓ SPECIFICATIONS

Wavelength Range	400 - 1100 nm
Aperture Dimension	8.9 x 11.8 mm ²
Spatial Resolution	29.6 μm
Phase and Intensity Sampling	300 x 400 (>120 000 points)
Resolution (Phase)	< 2 nm RMS
Accuracy	15 nm RMS
Dynamic range	> 500 μm
Radius of Curvature range (*)	4 mm to + ∞ (*)
Curvature resolution	< 5.10 ⁻⁴ m ⁻¹
Maximum Numerical aperture (*)	0.5 (*)
Acquisition Rate	> 30 fps
Real-time processing frequency	3 fps (full resolution)
Dimensions (WxHxL)	54 x 46 x 79 mm
Weight	~250 g

(*) optional software necessary

→ **SID4-High Resolution** wave front sensor is adapted for optical metrology needs. It associates the SID4 ease of implementation with ultra high resolution. The SID4-HR gives an instantaneous measurement on the whole object to characterize.

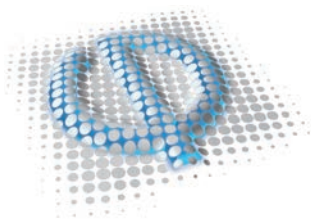
It is optimized to **surface inspection** (roughness, high frequency defects...) and **optical components characterization** (lens, objective, aspheric...).

The high performance camera increases the precision for laser characterization.

The 300 x 400 phase map sampling with such compactness make the SID4-HR a unique tool for optics and laser in research and industry.

↘ KEY FEATURES

- Very high resolution (400 x 300)
- Large analysis pupil (8,9 mm x 11,8 mm)
- High dynamic range
- Instantaneous measurement on a large field
- Optimal signal to noise ratio
- Compactness for easy implementation



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